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Docket No.: 0179-0170P
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Juergen MUELLER et al.

Application No.: 09/868,845

Confirmation No.: 6312

Filed: September 7, 2001

Art Unit: 2877

For: SCANNING MICROSCOPIC METHOD
HAVING HIGH AXIAL RESOLUTION

Examiner: G. J. Stock

**STATEMENT OF SUBSTANCE OF INTERVIEW IN
ACCORDANCE WITH MPEP §713.04**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Applicants submit herewith a statement on the substance of the telephonic interview held on August 7, 2006.


The Supervisor is thanked for conducting the interview on August 7, 2006. During the interview a petition filed June 10, 2005 and an associated Decision of November 2, 2005 were discussed. As a result of the interview, it is Applicants understanding that a corrected decision on petition will be sent showing all four (4) added inventors.

Should the Examiner have any questions regarding this matter, he is respectfully requested to contact Robert W. Downs (Reg. No. 48,222), who may be reached in the Washington, DC, area at (703) 205-8000.

If necessary, the Commissioner is hereby authorized in this, concurrent, and future replies, to charge payment or credit any overpayment to Deposit Account No. 02-2448 for any additional fees required under 37 C.F.R. §§ 1.16 or 1.17; particularly, extension of time fees.

Dated: August 8, 2006

Respectfully submitted,

By 
Terrell C. Birch
Registration No.: 19,382 #2827
BIRCH, STEWART, KOLASCH & BIRCH, LLP
8110 Gatehouse Road
Suite 100 East
P.O. Box 747
Falls Church, Virginia 22040-0747
(703) 205-8000
Attorney for Applicant